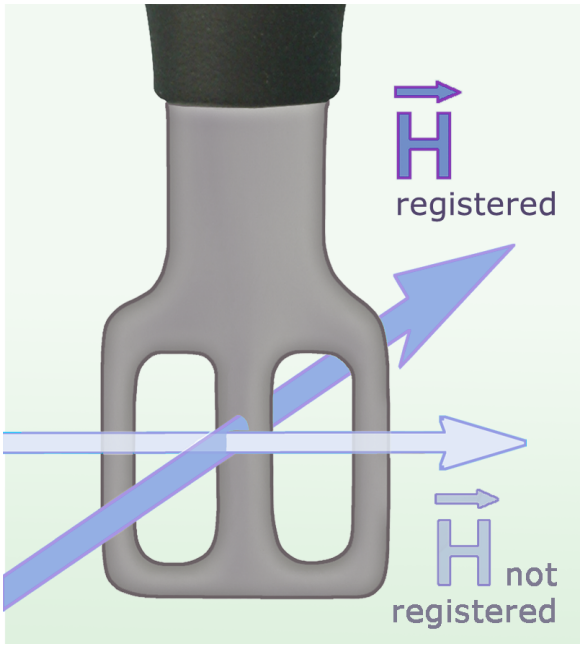
XF-R 100-1

H-Field Probe 30 MHz up to 6 GHz



Short description

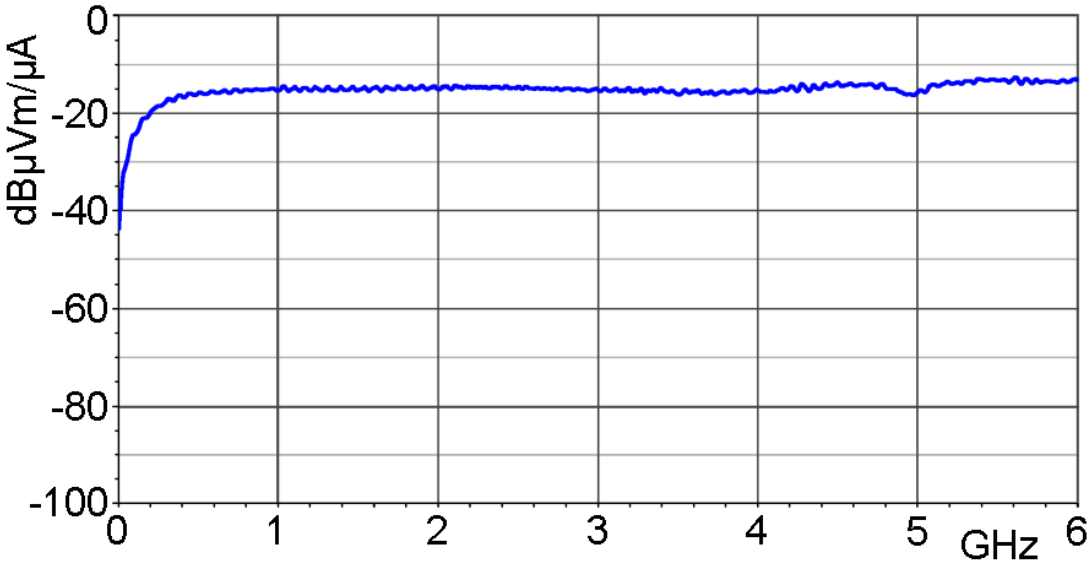
The XF-R 100-1 H-field probe is suitable for measurements around assemblies, devices or cables at a distance of up to approx. 3 cm. The H-field probe can identify larger components as potential sources of interference. The magnetic field probe has a very high bandwidth and linearity.

The XF-R 100-1 is a passive near-field probe. The probe head's size, and thus its resolution range, is between that of the XF-R 400-1 (25 mm) and XF-R 3-1 (3mm) probes. The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe has an internal terminating resistance.

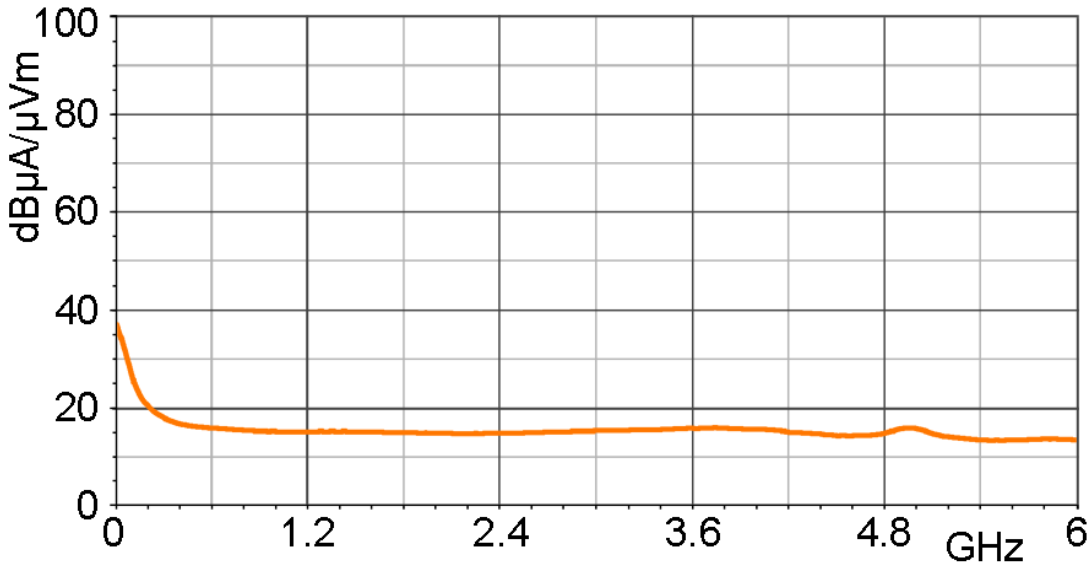
Technical parameters

Frequency range	30 MHz ... 6 GHz
Resolution	Ø ≈10 mm
Probe head dimensions:	≈ (10x10) mm
Connector - output	SMA, female, jack

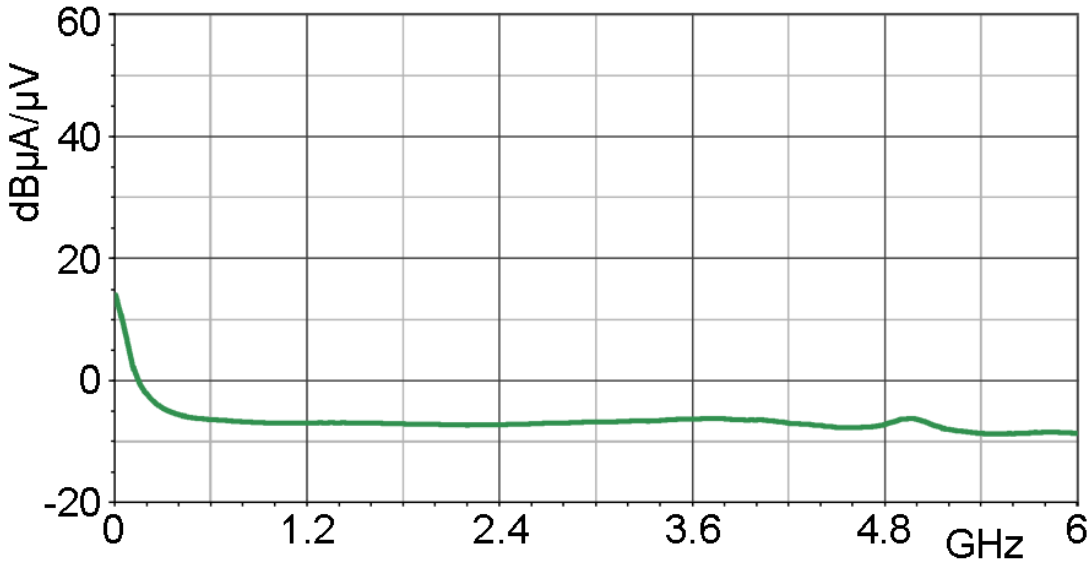
Frequency response [dBµV] / [dBµA/m]



H-field correction curve [dBµA/m] / [dBµV]



Current correction curve [dBµA] / [dBµV]



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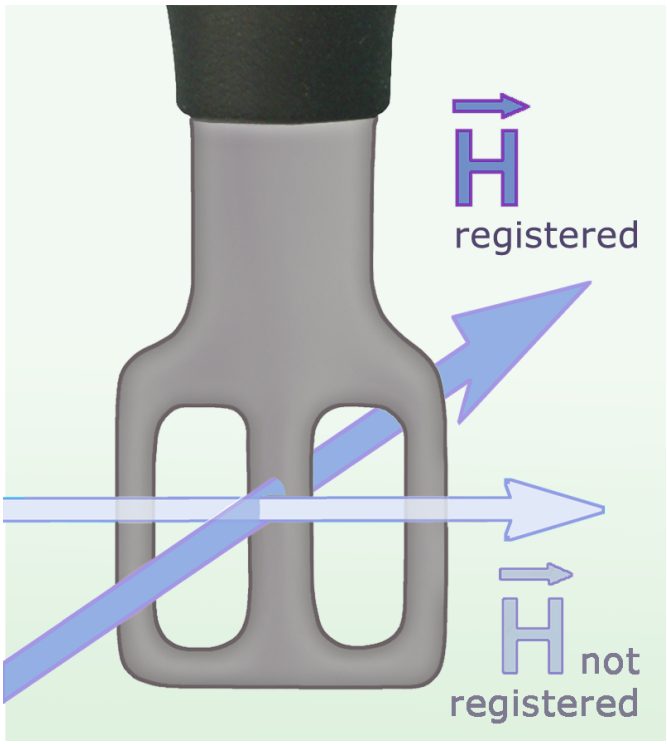
Measuring principles



Probe head